PATENT ASSIGNMENT COVER SHEET

Electronic Version v1.1
Stylesheet Version v1.2

EPAS ID: PAT4402014

SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	ASSIGNMENT

CONVEYING PARTY DATA

Name	Execution Date
SEMICONDUCTOR DIAGNOSTICS, INC.	04/20/2017

RECEIVING PARTY DATA

Name:	SEMILAB SEMICONDUCTOR PHYSICS LABORATORY CO., LTD.
Street Address:	PRIELLE KORNELIA U. 2
City:	BUDAPEST
State/Country:	HUNGARY
Postal Code:	H-1117

PROPERTY NUMBERS Total: 3

Property Type	Number
Application Number:	09672351
Application Number:	09810789
Application Number:	11191093

CORRESPONDENCE DATA

Fax Number: (877)769-7945

Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.

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ATTORNEY DOCKET NUMBER:	02695-0024001, -026, -035
NAME OF SUBMITTER:	ROSELYNN SCARFO
SIGNATURE:	/Roselynn Scarfo/
DATE SIGNED:	05/08/2017

Total Attachments: 4
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CONFIRMATORY ASSIGNMENT

This Confirmatory Patent Assignment (this "Assignment") dated effective June 11, 2009, by and between Semiconductor Diagnostics, Inc., a Florida corporation, whose principal place of business is at 3650 Spectrum Boulevard, Suite 130, Tampa, Florida 33612 ("ASSIGNOR"), and SEMILAB Semiconductor Physics Laboratory Co., Ltd., whose principal place of business is at Prielle Kornelia u. 2, H-1117, Budapest, Hungary ("ASSIGNEE")

WHEREAS, pursuant to that certain Asset Purchase Agreement between ASSIGNOR and ASSIGNEE dated as of June 11, 2009 (the "Asset Purchase Agreement"), and the Exclusive License Agreement between ASSIGNOR and ASSIGNEE dated as of June 11, 2009 (the "Exclusive License Agreement"), the ASSIGNOR agreed to transfer, sell and assign to ASSIGNEE all of its right, title and interest in and to its Intellectual Property, including, but not limited to, the patents listed on the attached Exhibit A (the "PATENTS").

NOW, THEREFORE, for good and valuable consideration, the receipt and sufficiency of which is hereby acknowledged, ASSIGNOR hereby confirms having assigned, transferred, conveyed, and delivered to the ASSIGNEE, its successors and assigns, effective as of the date first referred above, all right, title, and interest of the ASSIGNOR in and to the PATENTS; the same to be held and enjoyed by the ASSIGNEE for its own use and enjoyment and for the use and enjoyment of its successors, assigns and other legal representatives, to the end of the term or terms for which the PATENTS are issued, granted, reissued, or extended, as fully and entirely as the same would have been held and enjoyed by the ASSIGNOR.

IN WITNESS WHEREOF, the undersigned has caused this Confirmatory Assignment to be duly executed and delivered on this 20 day of April 2017.

[Signature Pages Follow]

Semiconductor Diagnostics, Inc., a Florida corporation, ("ASSIGNOR").

Signature: _____ Date: April 20, 2017

Name: Jacek Lagowski

Title: President

STATE OF FLORIDA
COUNTY OF Hillsborough

The foregoing instrument was acknowledged before me this 20 day of April, 2017, by Jacek Lagowski.

_____
(Signature of Notary Public-State of Florida)

Amy M. Mueller
(Name of Notary Typed, Printed, or Stamped)

Personally Known X OR Produced Identification _____
Type of Identification Produced _____

SEMILAB Semiconductor Physics Laboratory Co., Ltd., ("ASSIGNEE")

Signature: _____ Date: April 26, 2017

Name: Tibor PAVELKA

Title: CEO & President

51052415.doc

Exhibit A

PATENTS

Title	Application No./ Patent No.	Filing Date/ Issue Date	Inventor(s)	Assignee
METHOD FOR FAST AND ACCURATE DETERMINATION OF THE MINORITY CARRIER DIFFUSION LENGTH FROM SIMULTANEOUSLY MEASURED SURFACE PHOTOVOLTAGES	09/672,351 6,512,384	Sep. 28, 2000 Jan. 28, 2003	Jacek Lagowski, Vladimir Faifer, Andrei Aleinikov	SEMICONDUCTOR DIAGNOSTICS, INC.
STEADY STATE METHOD FOR MEASURING THE THICKNESS AND THE CAPACITANCE OF ULTRA THIN DIELECTRIC IN THE PRESENCE OF SUBSTANTIAL LEAKAGE CURRENT	09/810,789 6,597,193	Mar. 16, 2001 Jul. 22, 2003	Jacek Lagowski, Alexander Savtchouk, Marshall D. Wilson From	SEMICONDUCTOR DIAGNOSTICS, INC.
NON-CONTACT METHOD FOR ACQUIRING CHARGE-VOLTAGE DATA ON MINIATURE TEST AREAS OF SEMICONDUCTOR PRODUCT WAFERS	11/191,093 7,202,691	Jul 27, 2005 Apr 10, 2007	Jacek Lagowski, Piotr Edelman, Dmitriy Marinskiy, Joseph Nicholas Kochey, Carlos Almeida	SEMICONDUCTOR DIAGNOSTICS, INC.

RECORDED: 05/08/2017

PATENT
REEL: 042271 FRAME: 0794